

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (Currently Amended) A field-effect transistor comprising a Group III nitride semiconductor layer structure including a heterojunction formed by a channel layer and an electron supply layer, a source electrode and a drain electrode formed on the semiconductor layer structure while being separated from each other, a gate electrode arranged between said source electrode and said drain electrode, and an insulating film formed on said Group III nitride semiconductor layer,

wherein, said gate electrode has a field plate portion formed on said insulating film while said field plate portion has a visored shape that overhangs a gate side of said insulating film between said gate electrode and said drain electrode, and said insulating film has a multilayered film including a first insulating film and a second insulating film, said first insulating film being made of a compound containing silicon and nitrogen as constituent elements, said second insulating film having a dielectric constant lower than that of said first insulating film.

2. (Original) A field-effect transistor according to claim 1, wherein, second insulating film is laminated on said first insulating film.

3. (Previously Presented) A field-effect transistor according to claim 1, wherein, the thickness of said first insulating film is not more than 150 nm.

4. (Previously Presented) A field-effect transistor according to claim 1, wherein, a dielectric constant of said second insulating film is not more than 3.5.

5. (Previously Presented) A field-effect transistor according to claim 1, wherein, said insulating film including said multilayered film is formed while being separated from said gate electrode, and said second insulating film is provided between said first insulating film and said gate electrode.

6. (Previously Presented) A field-effect transistor according to claim 5, wherein, said second insulating film is provided between said first insulating film and said gate electrode and said second insulating film is positioned below said field plate portion, and said multilayered film including said first insulating film and said second insulating film is positioned between a drain-side end portion of said field plate portion and said drain electrode.

7. (Previously Presented) A field-effect transistor according to claim 1, further comprising a third insulating film on said second insulating film, the third insulating film being made of a compound containing silicon and nitrogen as the constituent elements.

8. (Currently Amended) A field-effect transistor comprising a Group III nitride semiconductor layer structure including a heterojunction formed by a channel layer and an electron supply layer, a source electrode and a drain electrode formed on the semiconductor layer structure while being separated from each other, a gate electrode arranged between said source electrode and said drain electrode, and an insulating film formed on said Group III nitride semiconductor layer,

wherein, said gate electrode has a field plate portion formed on said insulating film while said field plate portion has a visored shape that overhangs a gate side of said insulating film between said gate electrode and said drain electrode, and said insulating film is made of a compound containing silicon, nitrogen, and oxygen as constituent elements.

9. (Currently Amended) A field-effect transistor comprising a Group III nitride semiconductor layer structure including a heterojunction formed by a channel layer and an electron supply layer, a source electrode and a drain electrode formed on the semiconductor layer structure while being separated from each other, a gate electrode arranged between said source electrode and said drain electrode, and an insulating film formed on said Group III nitride semiconductor layer,

wherein, said gate electrode has a field plate portion formed on said insulating film while said field plate portion has a visored shape that overhangs a gate side of said insulating

film between said gate electrode and said drain electrode, and said insulating film has dielectric constants not more than 3.5.

10. (Currently Amended) A field-effect transistor comprising a Group III nitride semiconductor layer structure including a heterojunction formed by a channel layer and an electron supply layer, a source electrode and a drain electrode formed on the semiconductor layer structure while being separated from each other, a gate electrode arranged between said source electrode and said drain electrode, and an insulating film formed on said Group III nitride semiconductor layer,

wherein, said gate electrode has a field plate portion formed on said insulating film while said field plate portion has a visored shape that overhangs a gate side of said insulating film between said gate electrode and said drain electrode, and said gate electrode side of said insulating film between said gate electrode and said drain electrode is made of an insulating material having dielectric constants not more than 4, and said drain electrode side of said insulating film is made of an insulating material containing silicon and nitrogen as constituent elements.

11. (Original) A field-effect transistor according to claim 10, wherein, said drain electrode side of said insulating film is made of an insulating material containing silicon, nitrogen, and oxygen as the constituent elements.

12. (Currently Amended) A field-effect transistor comprising a Group III nitride semiconductor layer structure including a heterojunction formed by a channel layer and an electron supply layer, a source electrode and a drain electrode formed on the semiconductor layer structure while being separated from each other, a gate electrode arranged between said source electrode and said drain electrode, and an insulating film formed on said Group III nitride semiconductor layer,

wherein, said gate electrode has a field plate portion formed on said insulating film while said field plate portion has a visored shape that overhangs a gate side of said insulating film between said gate electrode and said drain electrode, and said drain electrode side is lower than said gate electrode side in a dielectric constant of a capacity formed by said field

plate portion, said Group III nitride semiconductor layer, and said insulating film sandwiched therebetween.

13. (Original) A field-effect transistor according to claim 12, wherein, a part of said insulating film is a multilayered film including a first insulating film and a second insulating film, said first insulating film being made of a compound containing silicon and nitrogen as constituent elements, said second insulating film having a dielectric constant lower than that of said first insulating film, and said gate electrode side is formed by a single-layer film of the first insulating film and said drain electrode side is formed by the multilayered film including said first insulating film and said second insulating film in said insulating film between said field plate portion and a surface of said semiconductor layer structure.

14. (Currently Amended) A field-effect transistor according to claim 1, wherein, said semiconductor layer structure includes **[[a]]** said channel layer made of $\text{In}_x\text{Ga}_{1-x}\text{N}$ ($0 \leq x \leq 1$) and **[[an]]** said electron supply layer made of $\text{Al}_y\text{Ga}_{1-y}\text{N}$ ($0 < y \leq 1$).

15. (Original) A field-effect transistor according to claim 1, wherein, contact layers are arranged between said source electrode and a surface of said semiconductor layer structure and between said drain electrode and a surface of said semiconductor layer structure, respectively.

16. (Original) A field-effect transistor according to claim 15, wherein, said contact layer is formed by an undoped AlGa_N layer.

17. (Original) A field-effect transistor according to claim 16, wherein, said field plate portion extends to an upper portion of said contact layer.

18. (Previously Presented) A field-effect transistor according to claim 1, wherein, said semiconductor layer structure has a structure in which the channel layer made of $\text{In}_x\text{Ga}_{1-x}\text{N}$

xN ($0 \leq x \leq 1$), the electron supply layer made of $Al_yGa_{1-y}N$ ($0 < y \leq 1$), and a cap layer made of GaN are sequentially laminate.

19. (Currently Amended) A field-effect transistor comprising a Group III nitride semiconductor layer structure including a heterojunction formed by a channel layer and an electron supply layer, a source electrode and a drain electrode formed on the semiconductor layer structure while being separated from each other, a gate electrode arranged between said source electrode and said drain electrode, and an insulating film formed on said Group III nitride semiconductor layer,

wherein, said gate electrode has a field plate portion formed on said insulating film while said field plate portion has a visored shape that overhangs a gate side of said insulating film between said gate electrode and said drain electrode, and said insulating film has a multilayered film including a first insulating film and a second insulating film, said first insulating film being made of a compound containing silicon and nitrogen as constituent elements, and said second insulating film having a dielectric constant lower than that of said first insulating film,

wherein a size of said field plate is not lower than $0.3 \mu m$.

20. (Previously Presented) A field-effect transistor according to claim 19, wherein a size of said field plate is not lower than $0.5 \mu m$.

21. (Previously Presented) A field-effect transistor according to claim 19, wherein a size of said field plate portion is not more than 70% of a distance between said gate electrode and said drain electrode.